

**High-Frequency NPN Transistor Array For Low-Power Applications at Frequencies Up to 1.5GHz**

The CA3227 consists of five general purpose silicon NPN transistors on a common monolithic substrate. Each of the transistors exhibits a value of  $f_T$  in excess of 3GHz, making them useful from DC to 1.5GHz. The monolithic construction of these devices provides close electrical and thermal matching of the five transistors.

**Ordering Information**

PART NUMBER (BRAND)	TEMP. RANGE (°C)	PACKAGE	PKG. NO.
CA3227E	-55 to 125	16 Ld PDIP	E16.3
CA3227M (3227)	-55 to 125	16 Ld SOIC	M16.15
CA3227M96 (3227)	-55 to 125	16 Ld SOIC Tape and Reel	M16.15

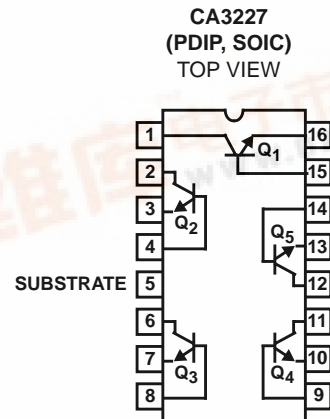
**Features**

- Gain-Bandwidth Product ( $f_T$ ) . . . . . >3GHz
- Five Transistors on a Common Substrate

**Applications**

- VHF Amplifiers
- VHF Mixers
- Multifunction Combinations - RF/Mixer/Oscillator
- IF Converter
- IF Amplifiers
- Sense Amplifiers
- Synthesizers
- Synchronous Detectors
- Cascade Amplifiers

**Pinout**



# CA3227

## Absolute Maximum Ratings

Collector to Emitter Voltage ( $V_{CEO}$ )	8V
Collector to Base Voltage ( $V_{CBO}$ )	12V
Collector to Substrate Voltage ( $V_{CIO}$ , Note 1)	20V
Collector Current ( $I_C$ )	20mA

## Operating Conditions

Temperature Range	-55°C to 125°C
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## Thermal Information

Thermal Resistance (Typical, Note 2)	$\theta_{JA}$ (°C/W)
16 Ld PDIP Package	90
16 Ld SOIC Package	185
Maximum Power Dissipation (Any One Transistor)	85mW
Maximum Junction Temperature (Die)	175°C
Maximum Junction Temperature (Plastic Package)	150°C
Maximum Storage Temperature Range	-65°C to 150°C
Maximum Lead Temperature (Soldering 10s)	300°C (SOIC - Lead Tips Only)

**CAUTION:** Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

### NOTES:

- The collector of each transistor of these devices is isolated from the substrate by an integral diode. The substrate (Terminal 5) must be connected to the most negative point in the external circuit to maintain isolation between transistors and to provide for normal transistor action.
- $\theta_{JA}$  is measured with the component mounted on an evaluation PC board in free air.

## Electrical Specifications $T_A = 25^\circ\text{C}$

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS	
<b>DC CHARACTERISTICS FOR EACH TRANSISTOR</b>							
Collector to Base Breakdown Voltage	$V_{(BR)CBO}$	$I_C = 10\mu\text{A}$ , $I_E = 0$	12	20	-	V	
Collector to Emitter Breakdown Voltage	$V_{(BR)CEO}$	$I_C = 1\text{mA}$ , $I_B = 0$	8	10	-	V	
Collector to Substrate Breakdown Voltage	$V_{(BR)CIO}$	$I_{C1} = 10\mu\text{A}$ , $I_B = 0$ , $I_E = 0$	20	-	-	V	
Emitter Cutoff Current (Note 3)	$I_{EBO}$	$V_{EB} = 4.5\text{V}$ , $I_C = 0$	-	-	10	$\mu\text{A}$	
Collector Cutoff Current	$I_{CEO}$	$V_{CE} = 5\text{V}$ , $I_B = 0$	-	-	1	$\mu\text{A}$	
Collector Cutoff Current	$I_{CBO}$	$V_{CB} = 8\text{V}$ , $I_E = 0$	-	-	100	nA	
DC Forward Current Transfer Ratio	$h_{FE}$	$V_{CE} = 6\text{V}$	$I_C = 10\text{mA}$	-	110	-	
			$I_C = 1\text{mA}$	40	150	-	
			$I_C = 0.1\text{mA}$	-	150	-	
Base to Emitter Voltage	$V_{BE}$	$V_{CE} = 6\text{V}$	$I_C = 1\text{mA}$	0.62	0.71	0.82	V
Collector to Emitter Saturation Voltage	$V_{CE\text{ SAT}}$	$I_C = 10\text{mA}$ , $I_B = 1\text{mA}$	-	0.13	0.50	V	
Base to Emitter Saturation Voltage	$V_{BE\text{ SAT}}$	$I_C = 10\text{mA}$ , $I_B = 1\text{mA}$	0.74	-	0.94	V	

### NOTE:

- On small-geometry, high-frequency transistors, it is very good practice never to take the Emitter Base Junction into reverse breakdown. To do so may permanently degrade the  $h_{FE}$ . Hence, the use of  $I_{EBO}$  rather than  $V_{(BR)EBO}$ . These devices are also susceptible to damage by electrostatic discharge and transients in the circuits in which they are used. Moreover, CMOS handling procedures should be employed.

## CA3227

### Electrical Specifications T<sub>A</sub> = 25°C, 200MHz, Common Emitter, Typical Values Intended Only for Design Guidance

PARAMETER	SYMBOL		TEST CONDITIONS	TYPICAL VALUES	UNITS
<b>DYNAMIC CHARACTERISTICS FOR EACH TRANSISTOR</b>					
Input Admittance	Y <sub>11</sub>	b <sub>11</sub>	I <sub>C</sub> = 1mA, V <sub>CE</sub> = 5V	4	mS
		g <sub>11</sub>		0.75	mS
Output Admittance	Y <sub>22</sub>	b <sub>22</sub>	I <sub>C</sub> = 1mA, V <sub>CE</sub> = 5V	2.7	mS
		g <sub>22</sub>		0.13	mS
Forward Transfer Admittance	Y <sub>21</sub>	Y <sub>21</sub>	I <sub>C</sub> = 1mA, V <sub>CE</sub> = 5V	29.3	mS
		θ <sub>21</sub>		-33	Degrees
Reverse Transfer Admittance	Y <sub>12</sub>	Y <sub>12</sub>	I <sub>C</sub> = 1mA, V <sub>CE</sub> = 5V	0.38	mS
		θ <sub>12</sub>		-97	Degrees
Input Admittance	Y <sub>11</sub>	b <sub>11</sub>	I <sub>C</sub> = 10mA, V <sub>CE</sub> = 5V	4.8	mS
		g <sub>11</sub>		2.85	mS
Output Admittance	Y <sub>22</sub>	b <sub>22</sub>	I <sub>C</sub> = 10mA, V <sub>CE</sub> = 5V	2.75	mS
		g <sub>22</sub>		0.9	mS
Forward Transfer Admittance	Y <sub>21</sub>	Y <sub>21</sub>	I <sub>C</sub> = 10mA, V <sub>CE</sub> = 5V	95	mS
		θ <sub>21</sub>		-62	Degrees
Reverse Transfer Admittance	Y <sub>12</sub>	Y <sub>12</sub>	I <sub>C</sub> = 10mA, V <sub>CE</sub> = 5V	0.39	mS
		θ <sub>12</sub>		-97	Degrees
Small Signal Forward Current Transfer Ratio	h <sub>21</sub>		I <sub>C</sub> = 1mA, V <sub>CE</sub> = 5V	7.1	
			I <sub>C</sub> = 10mA, V <sub>CE</sub> = 5V	17	
<b>TYPICAL CAPACITANCE AT 1MHz, THREE-TERMINAL MEASUREMENT</b>					
Collector to Base Capacitance	C <sub>CB</sub>		V <sub>CB</sub> = 6V	0.3	pF
Collector to Substrate Capacitance	C <sub>CI</sub>		V <sub>CI</sub> = 6V	1.6	pF
Collector to Emitter Capacitance	C <sub>CCE</sub>		V <sub>CE</sub> = 6V	0.4	pF
Emitter to Base Capacitance	C <sub>EB</sub>		V <sub>EB</sub> = 3V	0.75	pF

### Spice Model (Spice 2G.6)

.model NPN

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+      BF = 2.610E + 02      BR = 4.401E + 00      IS = 6.930E - 16      RB = 130.0E + 00
+      RC = 1.000E + 01      RE = 7.396E - 01      VA = 6.300E + 01      VB = 2.208E + 00
+      IK = 1.000E - 01      ISE = 1.87E - 14      NE = 1.653E + 00      IKR = 1.000E - 02
+      ISC = 9.25E - 14      NC = 1.333E + 00      TF = 1.775E - 11      TR = 1.000E - 09
+      CJS = 1.800E - 12      CJE = 1.010E - 12      PE = 8.350E - 01      ME = 4.460E - 01
+      CJC = 9.100E - 13      PC = 3.850E - 01      MC = 2.740E - 01      KF = 0.000E + 00
+      AF = 1.000E + 00      EF = 1.000E + 00      FC = 5.000E - 01      PJS = 5.410E - 01
+      MJS = 3.530E - 01      RBM = 30.00      RBV = 100      IRB = 0.00

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Please Note: No measurements have been made to model the reverse AC operation (tr is an estimation).

Typical Performance Curves

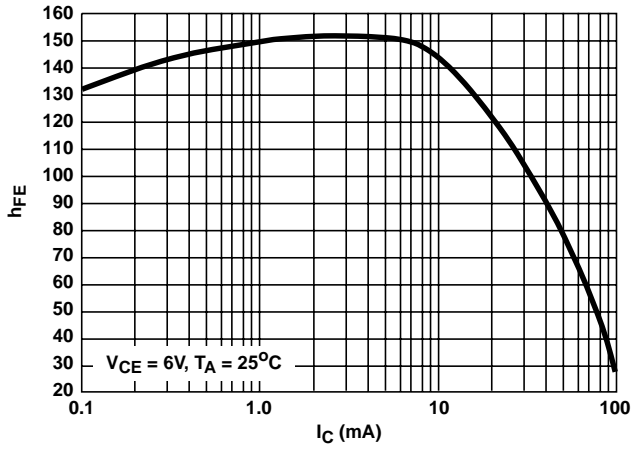


FIGURE 1.  $h_{FE}$  vs COLLECTOR CURRENT

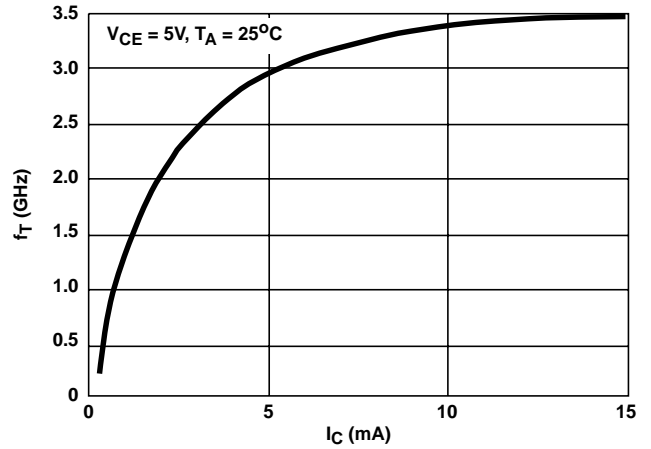


FIGURE 2.  $f_T$  vs COLLECTOR CURRENT

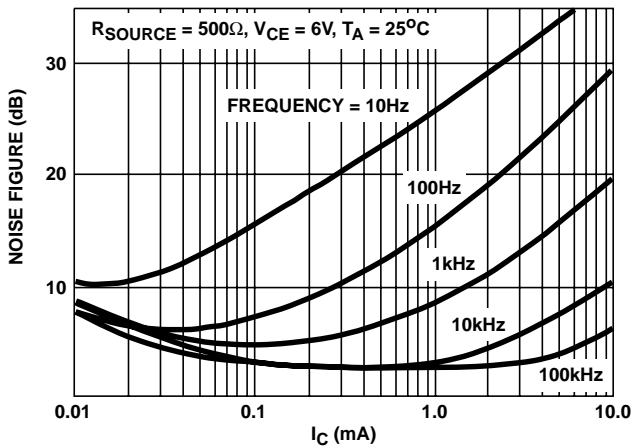


FIGURE 3. NOISE FIGURE vs COLLECTOR CURRENT

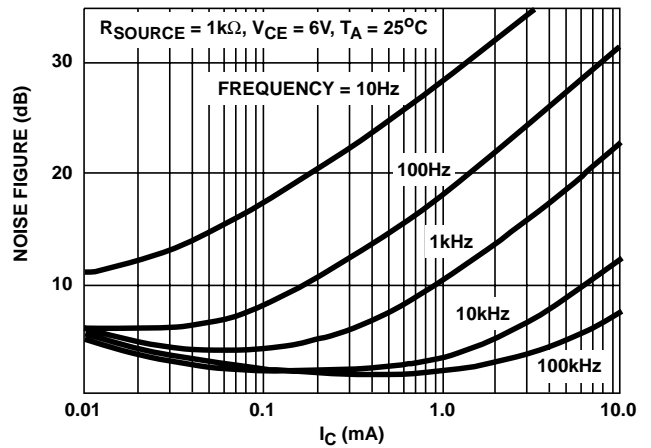


FIGURE 4. NOISE FIGURE vs COLLECTOR CURRENT

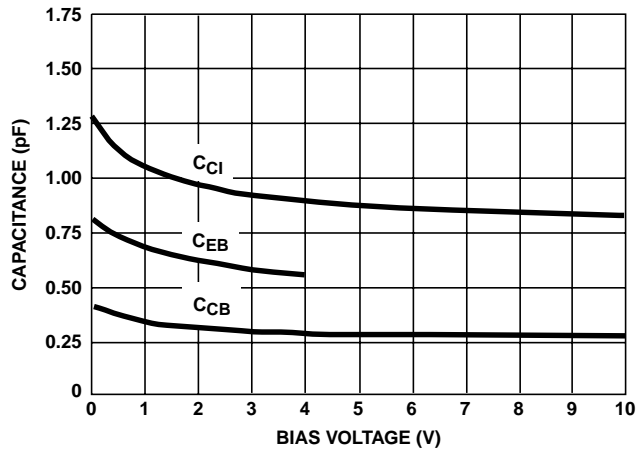


FIGURE 5. CAPACITANCE vs BIAS VOLTAGE

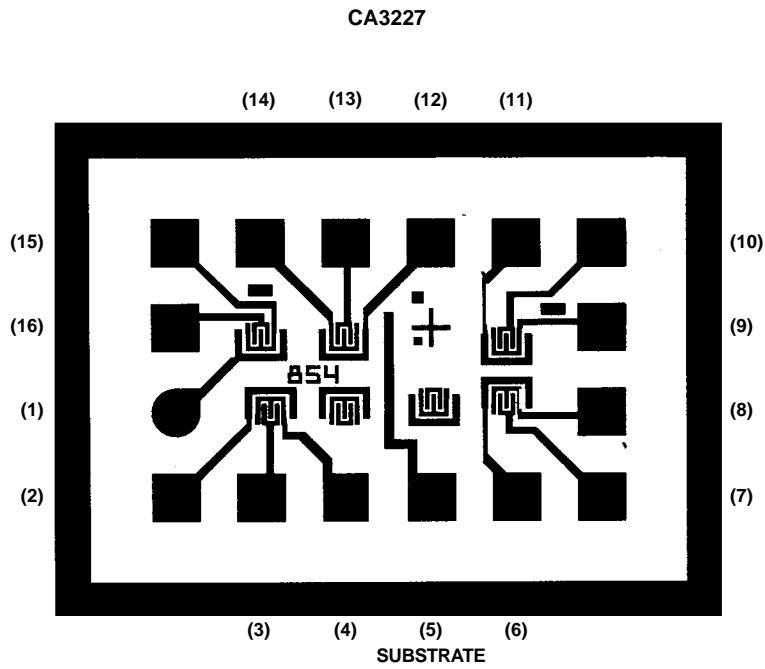
# CA3227

## Die Characteristics

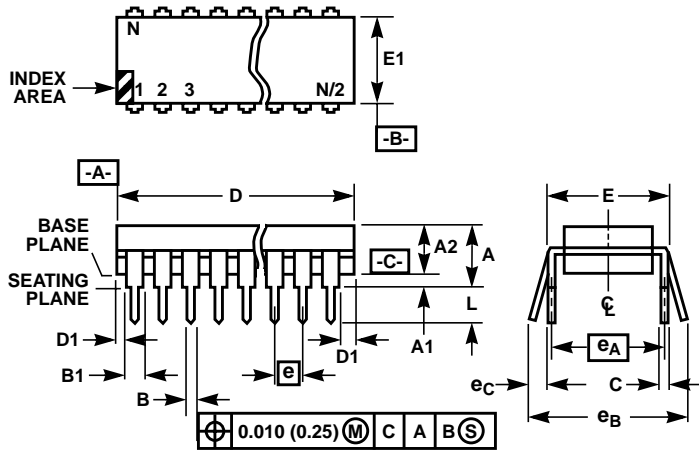
### DIE DIMENSIONS:

46 mils x 32 mils

## Metallization Mask Layout



Dual-In-Line Plastic Packages (PDIP)



NOTES:

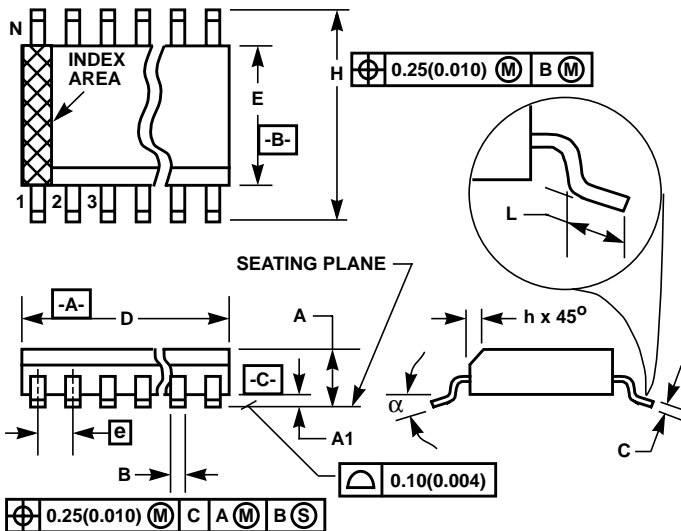
1. Controlling Dimensions: INCH. In case of conflict between English and Metric dimensions, the inch dimensions control.
2. Dimensioning and tolerancing per ANSI Y14.5M-1982.
3. Symbols are defined in the "MO Series Symbol List" in Section 2.2 of Publication No. 95.
4. Dimensions A, A1 and L are measured with the package seated in JEDEC seating plane gauge GS-3.
5. D, D1, and E1 dimensions do not include mold flash or protrusions. Mold flash or protrusions shall not exceed 0.010 inch (0.25mm).
6. E and e<sub>A</sub> are measured with the leads constrained to be perpendicular to datum -C-.
7. e<sub>B</sub> and e<sub>C</sub> are measured at the lead tips with the leads unconstrained. e<sub>C</sub> must be zero or greater.
8. B1 maximum dimensions do not include dambar protrusions. Dambar protrusions shall not exceed 0.010 inch (0.25mm).
9. N is the maximum number of terminal positions.
10. Corner leads (1, N, N/2 and N/2 + 1) for E8.3, E16.3, E18.3, E28.3, E42.6 will have a B1 dimension of 0.030 - 0.045 inch (0.76 - 1.14mm).

E16.3 (JEDEC MS-001-BB ISSUE D)  
16 LEAD DUAL-IN-LINE PLASTIC PACKAGE

SYMBOL	INCHES		MILLIMETERS		NOTES
	MIN	MAX	MIN	MAX	
A	-	0.210	-	5.33	4
A1	0.015	-	0.39	-	4
A2	0.115	0.195	2.93	4.95	-
B	0.014	0.022	0.356	0.558	-
B1	0.045	0.070	1.15	1.77	8, 10
C	0.008	0.014	0.204	0.355	-
D	0.735	0.775	18.66	19.68	5
D1	0.005	-	0.13	-	5
E	0.300	0.325	7.62	8.25	6
E1	0.240	0.280	6.10	7.11	5
e	0.100 BSC		2.54 BSC		-
e <sub>A</sub>	0.300 BSC		7.62 BSC		6
e <sub>B</sub>	-	0.430	-	10.92	7
L	0.115	0.150	2.93	3.81	4
N	16		16		9

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**Small Outline Plastic Packages (SOIC)**



**M16.15 (JEDEC MS-012-AC ISSUE C)  
16 LEAD NARROW BODY SMALL OUTLINE PLASTIC PACKAGE**

SYMBOL	INCHES		MILLIMETERS		NOTES
	MIN	MAX	MIN	MAX	
A	0.0532	0.0688	1.35	1.75	-
A1	0.0040	0.0098	0.10	0.25	-
B	0.013	0.020	0.33	0.51	9
C	0.0075	0.0098	0.19	0.25	-
D	0.3859	0.3937	9.80	10.00	3
E	0.1497	0.1574	3.80	4.00	4
e	0.050 BSC		1.27 BSC		-
H	0.2284	0.2440	5.80	6.20	-
h	0.0099	0.0196	0.25	0.50	5
L	0.016	0.050	0.40	1.27	6
N	16		16		7
$\alpha$	0°	8°	0°	8°	-

**NOTES:**

1. Symbols are defined in the "MO Series Symbol List" in Section 2.2 of Publication Number 95.
2. Dimensioning and tolerancing per ANSI Y14.5M-1982.
3. Dimension "D" does not include mold flash, protrusions or gate burrs. Mold flash, protrusion and gate burrs shall not exceed 0.15mm (0.006 inch) per side.
4. Dimension "E" does not include interlead flash or protrusions. Interlead flash and protrusions shall not exceed 0.25mm (0.010 inch) per side.
5. The chamfer on the body is optional. If it is not present, a visual index feature must be located within the crosshatched area.
6. "L" is the length of terminal for soldering to a substrate.
7. "N" is the number of terminal positions.
8. Terminal numbers are shown for reference only.
9. The lead width "B", as measured 0.36mm (0.014 inch) or greater above the seating plane, shall not exceed a maximum value of 0.61mm (0.024 inch).
10. Controlling dimension: MILLIMETER. Converted inch dimensions are not necessarily exact.

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